Notice of References Cited Application/Control No. 10/626,011 Examiner TuyetLien (Lien) T. Tran Applicant(s)/Patent Under Reexamination DE WAAL, ABRAHAM B. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,018,340	01-2000	Butler et al.	715/764
*	В	US-5,923,307	07-1999	Hogle, IV, Francis M.	345/4
*	С	US-6,832,355	12-2004	Duperrouzel et al.	715/788
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			•
	J	US-	_		
	К	US-			
	L	US-		·	
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s			·		
	Т			•		

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	×	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.